

FastScan AFM Workshop

A Bruker Meeting at Ole Miss



Wednesday, March 25th | 9:00am to 3:00pm
Center for Manufacturing Excellence Building, Rm 108

Please join us for an:

Ole Miss/Bruker FastScan AFM Workshop

If you are using an AFM, have plans to use atomic force microscopy in the future or are just curious about how fast an AFM can really scan or what can be seen with a fast scanning AFM, then this workshop is for you!

Bruker Senior Application Scientist, John Thornton, will present some of the latest advances in AFM microscopy and the increasingly popular PeakForce Tapping® mode.

We will be ready to discuss your AFM questions:

- How-to questions
- Instrument optimization
- Software manipulation
- Upgrades, etc.

The majority of the day, however, will be dedicated to hands-on demonstration and sample imaging with the Dimension FastScan AFM. Bring samples* and reserve a time slot for one-on-one time with our applications expert.

*Samples must be pre-cleared before the workshop. Contact John Thornton (john.thornton@bruker.com) to reserve a time slot and discuss your samples.

Lunch will be provided to attendees. Registration required.

FIRST 25 TO REGISTER WILL RECEIVE FREE AFM PROBES!

REGISTER ONLINE:

www.bruker.com/BNS-NA_workshops

